Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/509,336	MATSUDA ET AL.	
Examiner	Art Unit	
Yong S. Chong	1617	

SEARCHED					
Class	Subclass	Date	Examiner		
514	255.01	8/16/2006	YSC		
514	317	8/16/2006	YSC		
-					
		_			

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
-					

SEARCH (INCLUDING SEAF)
	DATE	EXMR
Inventor (EAST, PALM)	8/16/2006	YSC
Text (EAST, NPL)	8/16/2006	YSC